FIG. 1A

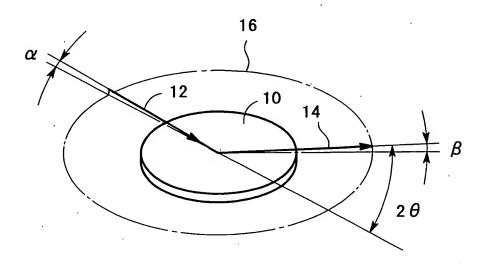
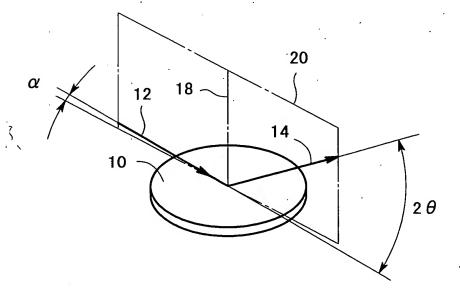


FIG. 1B



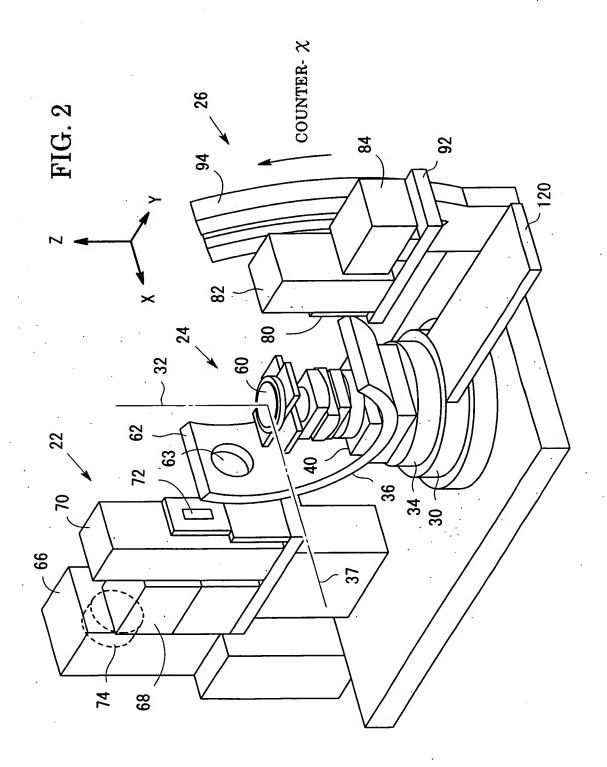


FIG. 3

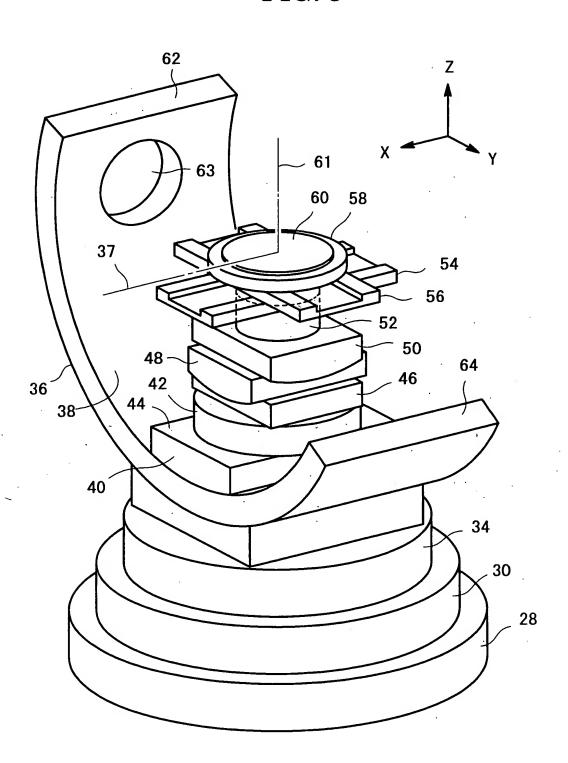
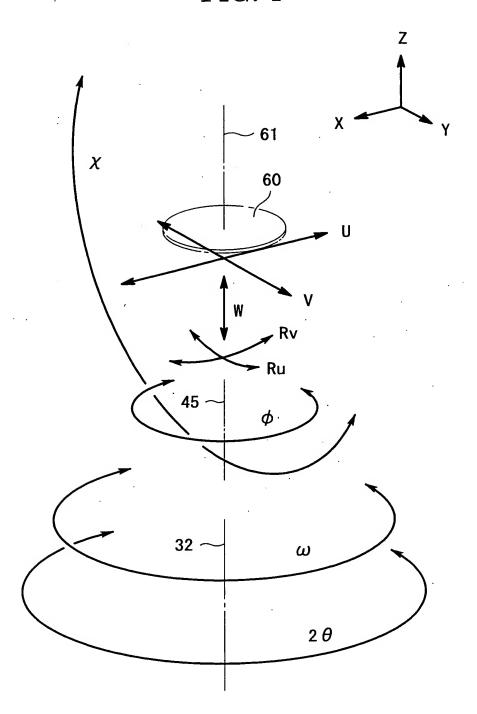
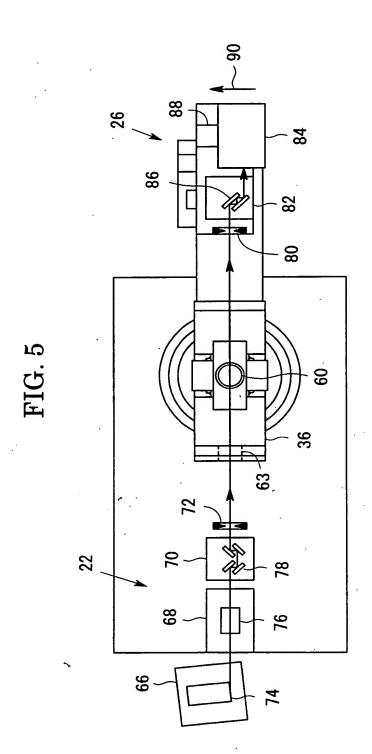


FIG. 4





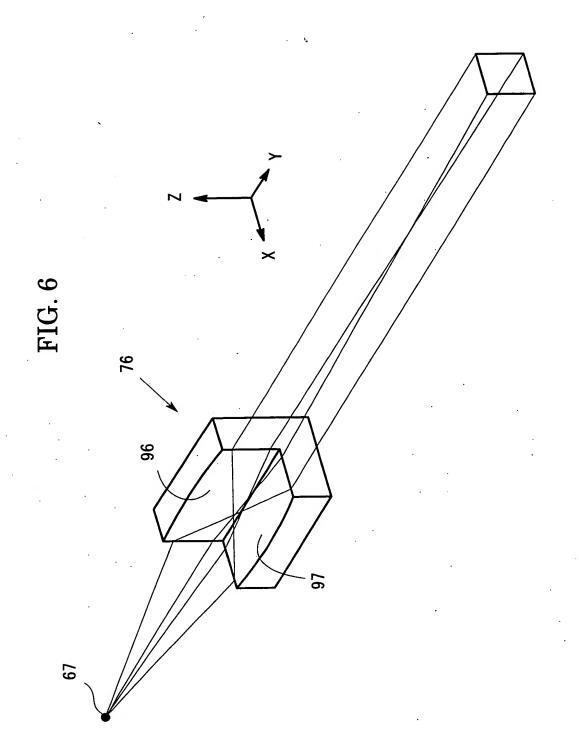


FIG. 7

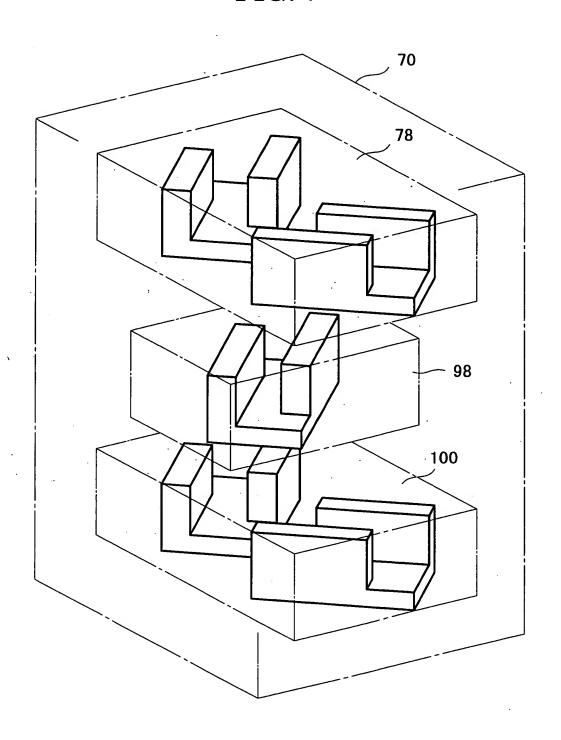


FIG. 8A

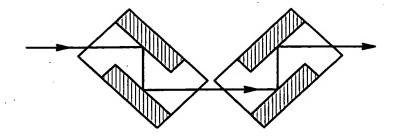


FIG. 8B

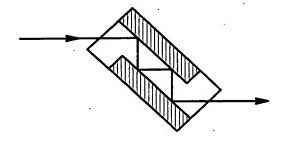


FIG. 8C



FIG. 9

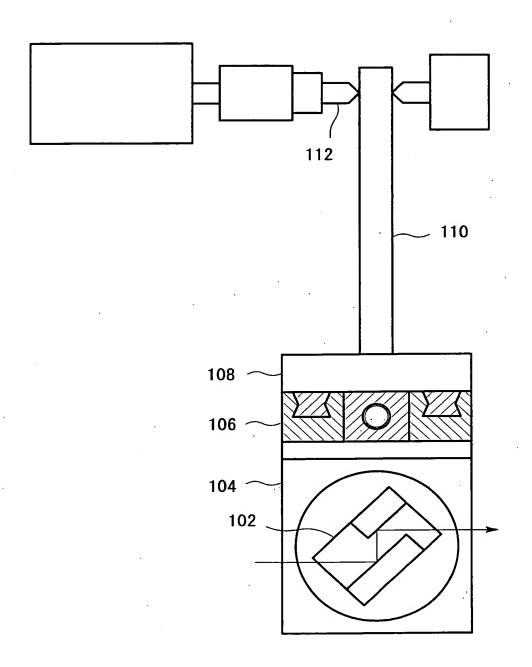
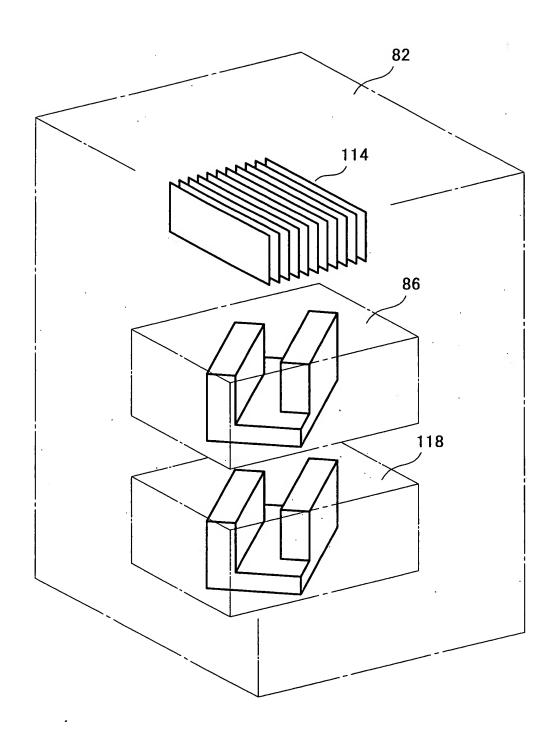


FIG. 10



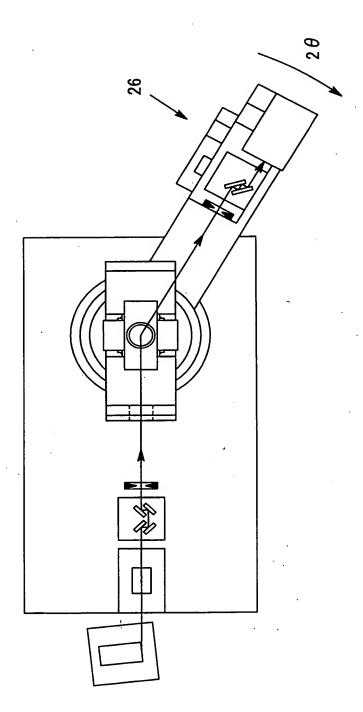
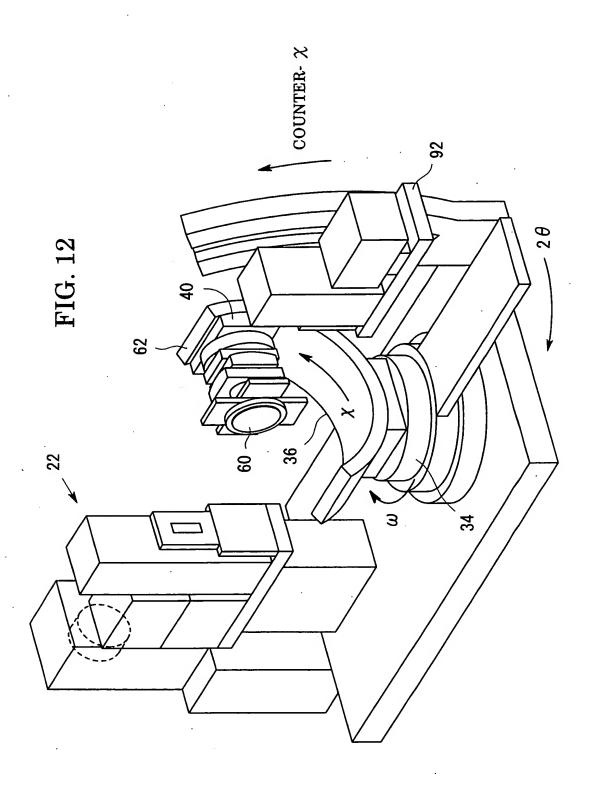
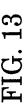
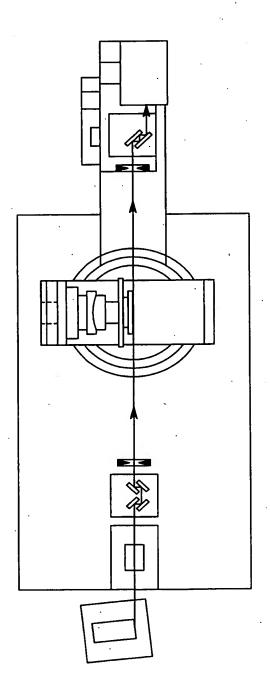
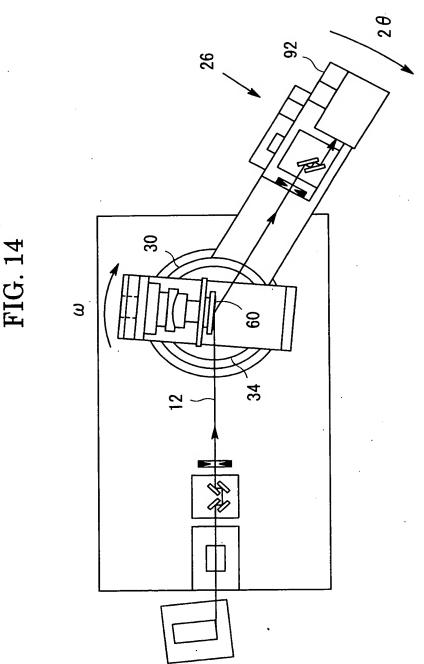


FIG. 11









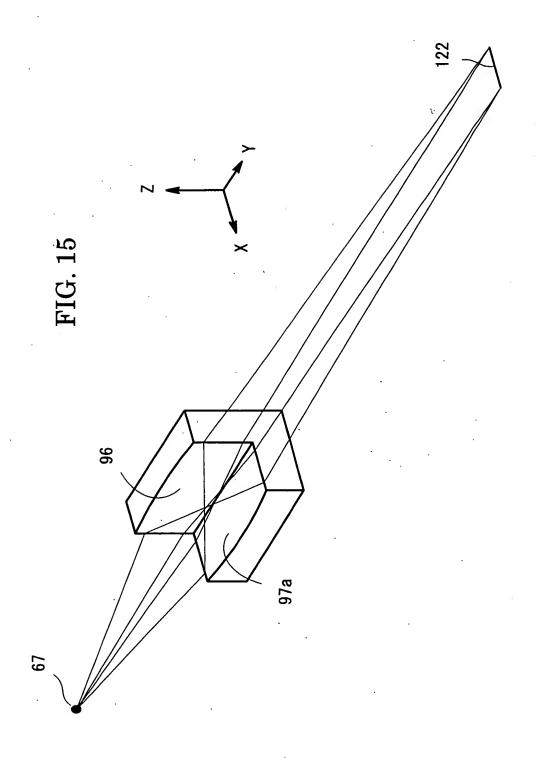


FIG. 16

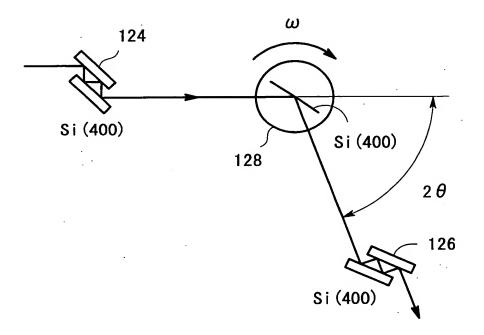


FIG. 17

IN-PLANE DIFFRACTION OF Si(400)

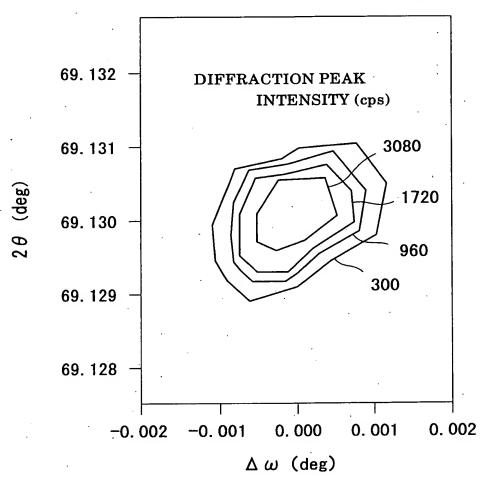


FIG. 18A

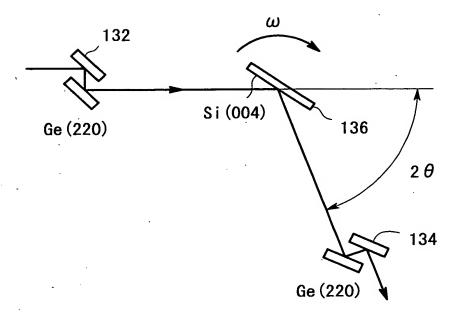


FIG. 18B

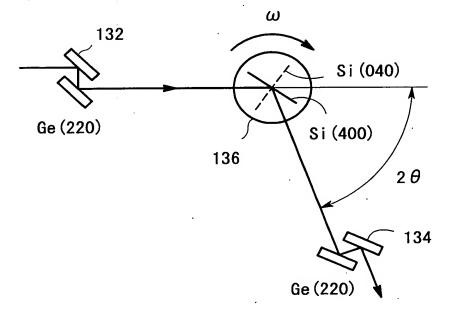


FIG. 19

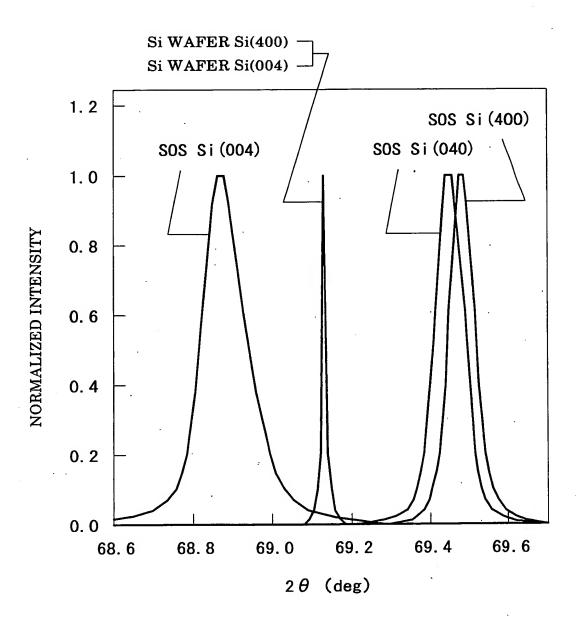


FIG. 20A

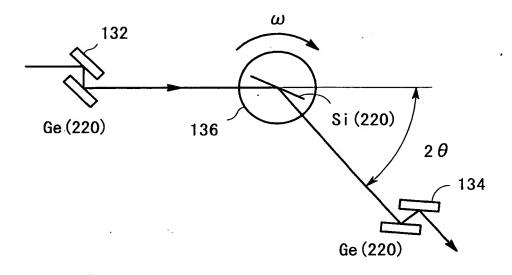


FIG. 20B

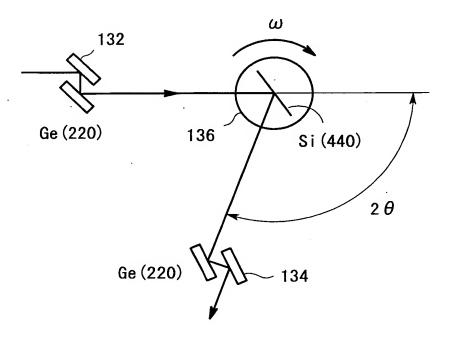


FIG. 21

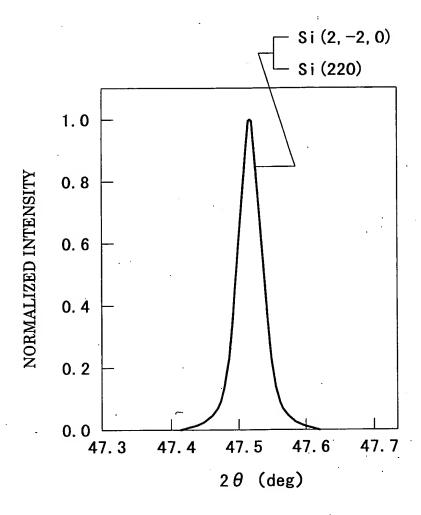
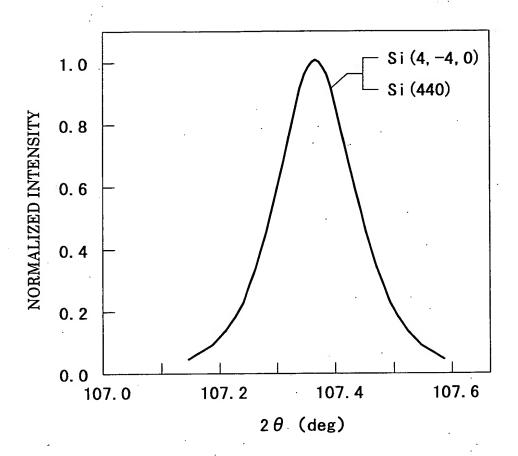
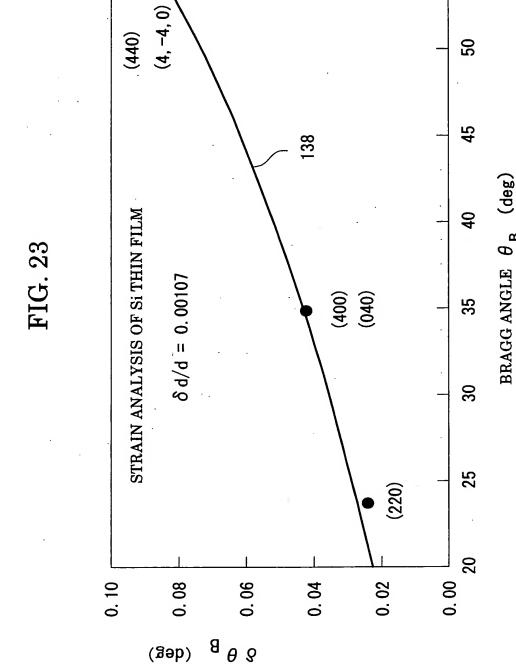


FIG. 22





DIEFRACTION PEAK WIDTH

55